Memory Elements

Unimplemented basic memory elements

- Periods of rapid toggling
- Trivial behavior

	Latch	Clock latch	Flip Flop	
D	trivial		good!	
T	rapid	rapid		
SR	good!			
JK	rapid	rapid	good!	

Practical Stuff

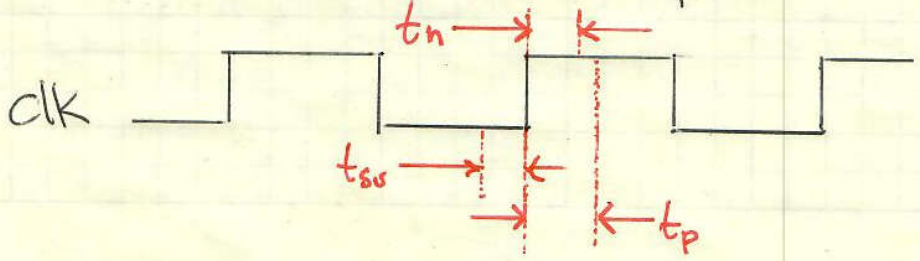
Initial state is set by asynchronous active low set or clear inputs.
Q=1 Q=0

<show schematic on hand out>

<show function table on hand out>

As long as set/clear is low output is held

Data into flip flop must be stable around clock edge

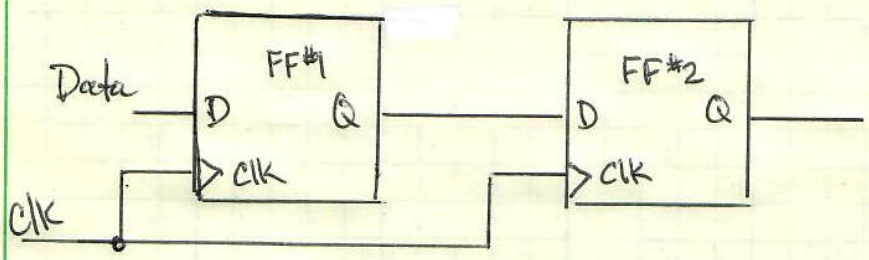


t_{su} - time before clock edge when data input must be stable

t_h - time after clock edge when data input must be stable

t_p - time after clock edge when new data output becomes valid

Violating t_{su} or t_h puts FF into an unknown state ≡ bad!



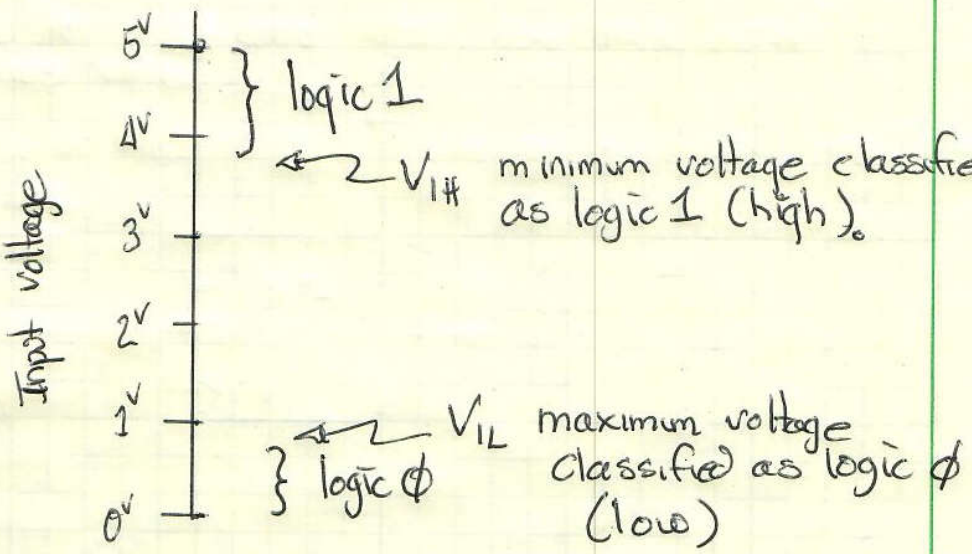
Q: What would happen if $t_p < t_h$?

A: The output of FF#1 would change during the hold time of FF#2. Resulting in an unknown state for FF#2.

This is such a common configuration that most flip flops will have

$$t_p \gg t_h$$

Input Voltages Assume our circuit is working with a 5v supply.

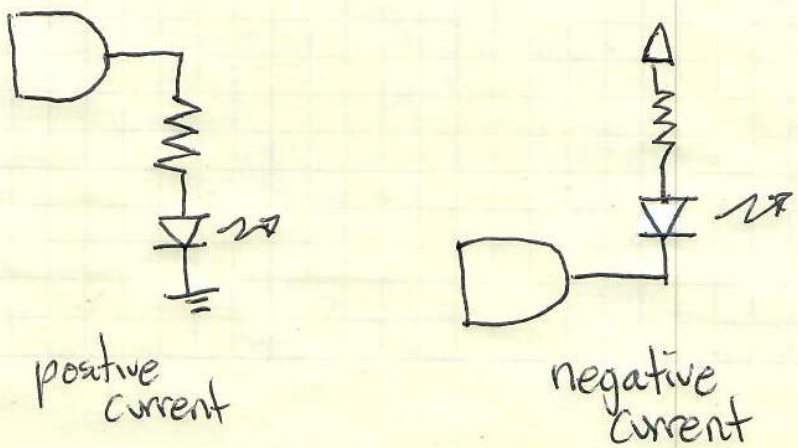


Output Voltages The output pins can only drive limited loads.

V_{OH} minimum logic 1 voltage under some load condition

V_{OL} maximum logic 0 voltage under some load condition

I_{out} maximum current (input negative, positive output)



Chip Nomenclature for 7400 Series IC

74 industrial
64 rare - extended temperature range
54 military

Next 2 letters describe silicon technology used
LS Bipolar transistors
HC CMOS

The numbers at the end specify function

74xx00 Quad 2-input NAND
74xx74 Dual D flip flop
74xx164 8-bit parallel out shift reg
74xx166 8-bit parallel in serial out

MC74HC73A

Dual J-K Flip-Flop with Reset

High–Performance Silicon–Gate CMOS

The MC74HC73A is identical in pinout to the LS73. The device inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LSTTL outputs.

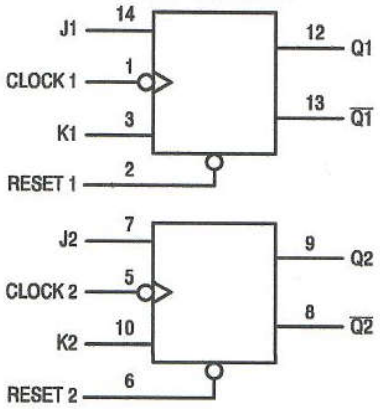
Each flip–flop is negative–edge clocked and has an active–low asynchronous reset.

The MC74HC73A is identical in function to the HC107, but has a different pinout.

Features

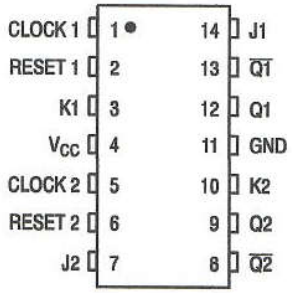
- Output Drive Capability: 10 LSTTL Loads
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V
- Low Input Current: 1.0 μA
- High Noise Immunity Characteristic of CMOS Devices
- In Compliance with the JEDEC Standard No. 7.0 A Requirements
- Chip Complexity: 92 FETs or 23 Equivalent Gates
- NLV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC–Q100 Qualified and PPAP Capable
- These are Pb–Free Devices

LOGIC DIAGRAM



PIN 4 = V_{CC}
PIN 11 = GND

PIN ASSIGNMENT



FUNCTION TABLE

Inputs				Outputs	
Reset	Clock	J	K	Q	$\overline{Q}$
L	X	X	X	L	H
H	↓	L	L	No Change	
H	↓	L	H	L	H
H	↓	H	L	H	L
H	↓	H	H	Toggle	
H	L	X	X	No Change	
H	H	X	X	No Change	
H	↑	X	X	No Change	

active low reset

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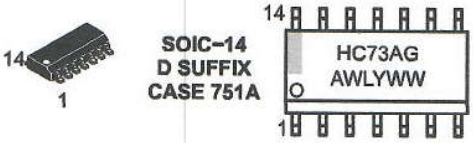
MARKING DIAGRAMS

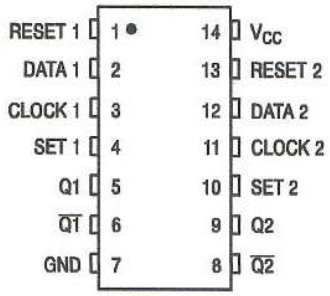


A = Assembly Location
WL, L = Wafer Lot
YY, Y = Year
WW, W = Work Week
G or ▪ = Pb–Free Package
(Note: Microdot may be in either location)

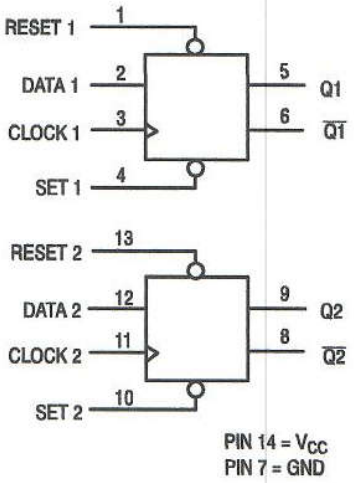
ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

PIN ASSIGNMENT



LOGIC DIAGRAM



PIN 14 = V_{CC}
PIN 7 = GND

FUNCTION TABLE

Active low set / reset

Inputs				Outputs	
Set	Reset	Clock	Data	Q	$\overline{Q}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H*	H*
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	No Change	
H	H	H	X	No Change	
H	H	↓	X	No Change	

*Both outputs will remain high as long as Set and Reset are low, but the output states are unpredictable if Set and Reset go high simultaneously.

MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	DC Supply Voltage (Referenced to GND)	– 0.5 to + 7.0	V
V_{in}	DC Input Voltage (Referenced to GND)	– 0.5 to V_{CC} + 0.5	V
V_{out}	DC Output Voltage (Referenced to GND)	– 0.5 to V_{CC} + 0.5	V
I_{in}	DC Input Current, per Pin	±20	mA
I_{out}	DC Output Current, per Pin	±25	mA
I_{CC}	DC Supply Current, V_{CC} and GND Pins	±50	mA
P_D	Power Dissipation in Still Air, SOIC Package†	500	mW
	TSSOP Package†	450	
T_{stg}	Storage Temperature	– 65 to + 150	°C
T_L	Lead Temperature, 1 mm from Case for 10 Seconds (SOIC or TSSOP Package)	260	°C
		300	

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range GND ≤ (V_{in} or V_{out}) ≤ V_{CC}.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

†Derating — SOIC Package: – 7 mW/°C from 65° to 125°C
TSSOP Package: – 6.1 mW/°C from 65° to 125°C

For high frequency or heavy load considerations, see Chapter 2 of the ON Semiconductor High–Speed CMOS Data Book (DL129/D).

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Min	Max	Unit
V_{CC}	DC Supply Voltage (Referenced to GND)		2.0	6.0	V
V_{in}, V_{out}	DC Input Voltage, Output Voltage (Referenced to GND)		0	V_{CC}	V
T_A	Operating Temperature, All Package Types		– 55	+ 125	°C
t_r, t_f	Input Rise and Fall Time (Figures 1, 2, 3)	V_{CC} = 2.0 V	0	1000	ns
		V_{CC} = 3.0 V	0	600	
		V_{CC} = 4.5 V	0	500	
		V_{CC} = 6.0 V	0	400	

MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	DC Supply Voltage (Referenced to GND)	– 0.5 to + 7.0	V
V_{in}	DC Input Voltage (Referenced to GND)	– 1.5 to V_{CC} + 1.5	V
V_{out}	DC Output Voltage (Referenced to GND)	– 0.5 to V_{CC} + 0.5	V
I_{in}	DC Input Current, per Pin	± 20	mA
I_{out}	DC Output Current, per Pin	± 25	mA
I_{CC}	DC Supply Current, V_{CC} and GND Pins	± 50	mA
P_D	Power Dissipation in Still Air SOIC Package†	500	mW
T_{stg}	Storage Temperature	– 65 to + 150	°C
T_L	Lead Temperature, 1 mm from Case for 10 Seconds (PSOIC Package)	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
†Derating — SOIC Package: – 7 mW/°C from 65° to 125°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range GND ≤ (V_{in} or V_{out}) ≤ V_{CC}.
Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Min	Max	Unit
V_{CC}	DC Supply Voltage (Referenced to GND)		2.0	6.0	V
V_{in}, V_{out}	DC Input Voltage, Output Voltage (Referenced to GND)		0	V_{CC}	V
T_A	Operating Temperature, All Package Types		– 55	+ 125	°C
t_r, t_f	Input Rise and Fall Time (Figure 1)	V_{CC} = 2.0 V	0	1000	ns
		V_{CC} = 4.5 V	0	500	
		V_{CC} = 6.0 V	0	400	

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

Symbol	Parameter	Test Conditions	V_{CC} V	Guaranteed Limit			Unit
				– 55 to 25°C	≤ 85°C	≤ 125°C	
V_{IH}	Minimum High–Level Input Voltage	V_{out} = 0.1 V or V_{CC} – 0.1 V $\|I_{out}\|$ ≤ 20 μA	2.0	1.5	1.5	1.5	V
			4.5	3.15	3.15	3.15	
			6.0	4.2	4.2	4.2	
V_{IL}	Maximum Low–Level Input Voltage	V_{out} = 0.1 V or V_{CC} – 0.1 V $\|I_{out}\|$ ≤ 20 μA	2.0	0.3	0.3	0.3	V
			4.5	0.9	0.9	0.9	
			6.0	1.2	1.2	1.2	
V_{OH}	Minimum High–Level Output Voltage	V_{in} = V_{IH} or V_{IL} $\|I_{out}\|$ ≤ 20 μA	2.0	1.9	1.9	1.9	V
			4.5	4.4	4.4	4.4	
			6.0	5.9	5.9	5.9	
		V_{in} = V_{IH} or V_{IL} $\|I_{out}\|$ ≤ 4.0 mA	4.5	3.98	3.84	3.70	
		$\|I_{out}\|$ ≤ 5.2 mA	6.0	5.48	5.34	5.20	
V_{OL}	Maximum Low–Level Output Voltage	V_{in} = V_{IH} or V_{IL} $\|I_{out}\|$ ≤ 20 μA	2.0	0.1	0.1	0.1	V
			4.5	0.1	0.1	0.1	
			6.0	0.1	0.1	0.1	
		V_{in} = V_{IH} or V_{IL} $\|I_{out}\|$ ≤ 4.0 mA	4.5	0.26	0.33	0.40	
		$\|I_{out}\|$ ≤ 5.2 mA	6.0	0.26	0.33	0.40	
I_{in}	Maximum Input Leakage Current	V_{in} = V_{CC} or GND	6.0	± 0.1	± 1.0	± 1.0	μA
I_{CC}	Maximum Quiescent Supply Current (per Package)	V_{in} = V_{CC} or GND I_{out} = 0 μA	6.0	4	40	80	μA

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

AC ELECTRICAL CHARACTERISTICS (C_L = 50 pF, Input $t_r = t_f$ = 6 ns)

Symbol	Parameter	V_{CC} V	Guaranteed Limit			Unit
			– 55 to 25°C	≤ 85°C	≤ 125°C	
f_{max}	Maximum Clock Frequency (50% Duty Cycle) (Figures 1 and 4)	2.0 4.5 6.0	6.0 30 35	4.8 24 28	4.0 20 24	MHz
t_{PLH}, t_{PHL}	Maximum Propagation Delay, Clock to Q or $\overline{Q}$ (Figures 1 and 4)	2.0 4.5 6.0	125 25 21	155 31 26	190 38 32	ns
t_{PLH}, t_{PHL}	Maximum Propagation Delay, Reset to Q or $\overline{Q}$ (Figures 2 and 4)	2.0 4.5 6.0	155 31 26	195 39 33	235 47 40	ns
t_{TLH}, t_{THL}	Maximum Output Transition Time, Any Output (Figures 1 and 4)	2.0 4.5 6.0	75 15 13	95 19 16	110 22 19	ns
C_{in}	Maximum Input Capacitance	—	10	10	10	pF

		Typical @ 25°C, V_{CC} = 5.0 V	
C_{PD}	Power Dissipation Capacitance (Per Flip−Flop)*	35	pF

* Used to determine the no−load dynamic power consumption: $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$.

TIMING REQUIREMENTS (Input $t_r = t_f$ = 6 ns)

Symbol	Parameter	V_{CC} V	Guaranteed Limit			Unit
			– 55 to 25°C	≤ 85°C	≤ 125°C	
t_{su}	Minimum Setup Time, J or K to Clock (Figure 3)	2.0 4.5 6.0	100 20 17	125 25 21	150 30 26	ns
t_h	Minimum Hold Time, Clock to J or K (Figure 3)	2.0 4.5 6.0	3 3 3	3 3 3	3 3 3	ns
t_{rec}	Minimum Recovery Time, Reset Inactive to Clock (Figure 2)	2.0 4.5 6.0	100 20 17	125 25 21	150 30 26	ns
t_w	Minimum Pulse Width, Clock (Figure 1)	2.0 4.5 6.0	80 16 14	100 20 17	120 24 20	ns
t_w	Minimum Pulse Width, Reset (Figure 2)	2.0 4.5 6.0	80 16 14	100 20 17	120 24 20	ns
t_r, t_f	Maximum Input Rise and Fall Times (Figure 1)	2.0 4.5 6.0	1000 500 400	1000 500 400	1000 500 400	ns

In addition to the three general routing outputs, LEs in an LAB have register chain outputs, which allows registers in the same LAB to cascade together. The register chain output allows the LUTs to be used for combinational functions and the registers to be used for an unrelated shift register implementation. These resources speed up connections between LABs while saving local interconnect resources.

LE Operating Modes

Cyclone IV LEs operate in the following modes:

- Normal mode
- Arithmetic mode

The Quartus® II software automatically chooses the appropriate mode for common functions, such as counters, adders, subtractors, and arithmetic functions, in conjunction with parameterized functions such as the library of parameterized modules (LPM) functions. You can also create special-purpose functions that specify which LE operating mode to use for optimal performance, if required.

Normal Mode

Normal mode is suitable for general logic applications and combinational functions. In normal mode, four data inputs from the LAB local interconnect are inputs to a four-input LUT (Figure 2–2). The Quartus II Compiler automatically selects the carry-in (`cin`) or the `data3` signal as one of the inputs to the LUT. LEs in normal mode support packed registers and register feedback.

Figure 2–2 shows LEs in normal mode.

Figure 2–2. Cyclone IV Device LEs in Normal Mode